Se	arch Note	es

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/624,524	LEE ET AL.		
Examiner	Art Unit		_
Nhan T. Tran	2622		

SEARCHED			
Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
search - s	rference text ee search printout	10/10/2007	NT

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Updated EAST search (USPAT, PGPUB, JPO, EPO, DERWENT, IBM_TDB)	10/10/2007	NT
Text search all classes 348, 455 and 379	10/10/2007	NT
Text search all classes in databases listed above	10/10/2007	NT
Updated inventorship search - see search history printout	10/10/2007	NT
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